

Notice of References Cited

Application/Control No.

10/072,313

Applicant(s)/Patent Under
Reexamination
SARIG, NIMROD

Examiner

Phallaka Kik

Art Unit

2825

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,345,514	09-1994	Mahdavi et al.	382/152
	B	US-4,579,455	04-1986	Levy et al.	356/394
	C	US-6,515,913	02-2003	Kajigaya et al.	365/189.02
	D	US-6,498,685	12-2002	Johnson, Kenneth C.	359/626
	E	US-2003/0099022	05-2003	Karin et al.	359/201
	F	US-4,559,603	12-1985	Yoshikawa, Ryoichi	716/5
	G	US-3,972,616	08-1976	Minami et al.	356/71
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 04311277 A	11-1992	Japan	SHOJI, HIROYUKI	G06F 15/62
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ong et al., "Acoustic microscopy reveals IC packaging hidden defects", Proceedings of the 1997 1st Electronic Packaging Technology Conference, 08 October 1997, pp. 297-303.
	V	Baraldi et al., "A refined gamma MAP SAR speckle filter with improved geometrical adaptivity", IEEE Transactions on Geoscience and Remote Sensing, Vol. 33, No. 5, September 1995, pp. 1245-1257.
	W	Hu et al., "Efficient and consistent method for superellipse detection", IEE Proceedings of Vision, Image and Signal Processing Vol. 148, No. 4, August 2001, pp. 227-233.
	X	Sheu et al., "Consistent symmetric axis method for robust detection of ellipses", IEE Proceedings of Vision, Image and Signal Processing, Vol. 144, No. 6, December 1997, pp. 332-338.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.